3	earcn Notes	

Application/Control No.	Applicant(s)/Patent under Reexamination	
10/813,367	LEE ET AL.	
Examiner	Art Unit	
Chau N. Nguyen	2831	

		 		
	SEARCHED			
Class	Subclass	Date	Examiner	
174	102SC	4/21/2005	CN	
	105SC		_	
	106Sc			
	120SC			

INT	INTERFERENCE SEARCHED			
Class	Subclass	Date	Examiner	
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S (INCLUDIN	EARCH NOT G SEARCH S	ES STRATEGY)
		DATE	EXMR
Text		4/21/2005	CN
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